CD74FCT573AT was not acquired from Harris Semiconductor.

TEXAS INSTRUMENTS

Data sheet acquired from Harris Semiconductor
SCHS260A

January 1997

CD74FCT573, CD74FCT573AT

BiCMOS FCT Interface Logic, Octal Transparent Latches, Three-State

NOT RECOMMENDED FOR NEW DESIGNS
Use CMOS Technology

Features

- **Buffered Inputs**
- **Typical Propagation Delay: 3.9ns at V_{CC} = 5V, T_A = 25°C, C_L = 50pF (CD74FCT573AT)**
- **SCR Latchup Resistant BiCMOS Process and Circuit Design**
- **FCTXXX Types**
  - **Speed of Bipolar FAST™/AS/S**
- **FCTXXXAT Types**
  - **30% Faster than FAST™/AS/S with Significantly Reduced Power Consumption**
- **48mA Output Sink Current**
- **Output Voltage Swing Limited to 3.7V at V_{CC} = 5V**
- **Controlled Output Edge Rates**
- **Input/Output Isolation to V_{CC}**
- **BiCMOS Technology with Low Quiescent Power**

Description

The CD74FCT573 and CD74FCT573AT octal transparent latches use a small geometry BiCMOS technology. The output stage is a combination of bipolar and CMOS transistors that limits the output HIGH level to two diode drops below V_{CC}. This resultant lowering of output swing (0V to 3.7V) reduces power bus ringing (a source of EMI) and minimizes V_{CC} bounce and ground bounce and their effects during simultaneous output switching. The output configuration also enhances switching speed and is capable of sinking 48 milliamperes.

The CD74FCT573 and CD74FCT573AT outputs are transparent to the inputs when the Latch Enable ($\overline{LE}$) is HIGH. When the Latch Enable ($\overline{LE}$) goes LOW, the data is latched. The Output Enable ($\overline{OE}$) controls the three-state outputs. When the Output Enable ($\overline{OE}$) is HIGH, the outputs are in the high impedance state. The latch operation is independent of the state of the Output Enable.

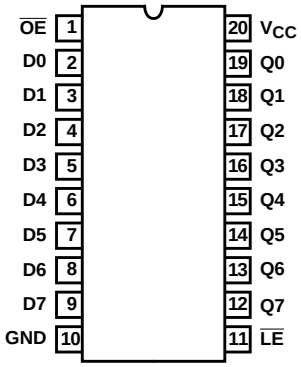
Ordering Information

PART NUMBER	TEMP. RANGE (°C)	PACKAGE	PKG. NO.
CD74FCT573ATE	0 to 70	20 Ld PDIP	E20.3
CD74FCT573M	0 to 70	20 Ld SOIC	M20.3
CD74FCT573SM	0 to 70	20 Ld SSOP	M20.209

NOTE: When ordering the suffix M and SM packages, use the entire part number. Add the suffix 96 to obtain the variant in the tape and reel.

Pinout

CD74FCT573, CD74FCT573AT
(PDIP, SOIC, SSOP)
TOP VIEW



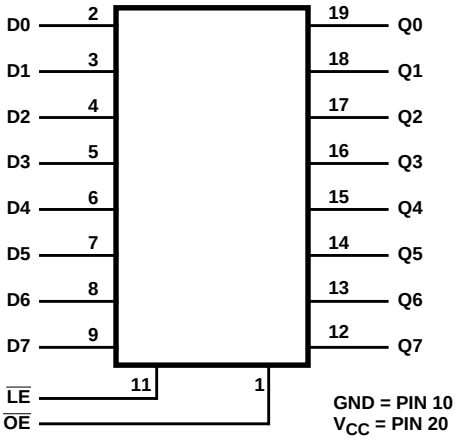
CAUTION: These devices are sensitive to electrostatic discharge. Users should follow proper IC Handling Procedures.

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File Number **2304.2**

Functional Diagram



TRUTH TABLE (Note 1)

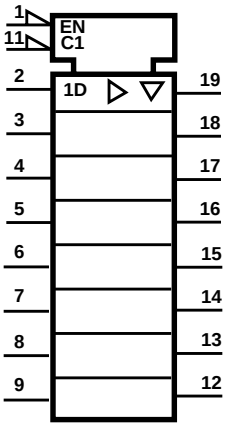
$\overline{\text{OUTPUT}}$ ENABLE	$\overline{\text{LATCH}}$ ENABLE	DATA	OUTPUT
L	H	H	H
L	H	L	L
L	L	l	L
L	L	h	H
H	X	X	Z

NOTE:

1. H = HIGH Voltage Level
   L = LOW Voltage Level
   l = Low voltage level one set up time prior to the high to low latch enable transition.
   h = High voltage level one set up time prior to the high to low latch enable transition.
   X = Irrelevant
   Z = High Impedance

IEC Logic Symbol

CD74FCT573, CD74FCT573AT



Absolute Maximum Ratings

DC Supply Voltage (V_{CC}) . . . . . -0.5V to 6V
DC Input Diode Current, I_{IK} (For V_I < -0.5V) . . . . . -20mA
DC Output Diode Current, I_{OK} (for V_O < -0.5V) . . . . . -50mA
DC Output Sink Current per Output Pin, IO 70mA
DC Output Source Current per Output Pin, IO . . . . . -30mA
DC V_{CC} Current (I_{CC}) 140mA
DC Ground Current (I_{GND}) 400mA

Operating Conditions

Operating Temperature Range (T_A) . . . . . 0^oC to 70^oC
Supply Voltage Range, V_{CC} . . . . . 4.75V to 5.25V
DC Input Voltage, V_I . . . . . 0 to V_{CC}
DC Output Voltage, V_O . . . . . 0 to ≤ V_{CC}
Input Rise and Fall Slew Rate, dt/dv . . . . . 0 to 10ns/V

Thermal Information

Thermal Resistance (Typical, Note 2)	θ_{JA} ($^oC/W$)
PDIP Package	135
SOIC Package	125
SSOP Package	130

Maximum Junction Temperature . . . . . 150^oC
Maximum Storage Temperature Range . . . . . -65^oC to 150^oC
Maximum Lead Temperature (Soldering 10s) . . . . . 300^oC
(SOIC and SSOP-Lead Tips Only)

CAUTION: Stresses above those listed in "Absolute Maximum Ratings" may cause permanent damage to the device. This is a stress only rating and operation of the device at these or any other conditions above those indicated in the operational sections of this specification is not implied.

NOTE:

2. θ_{JA} is measured with the component mounted on an evaluation PC board in free air.

Electrical Specifications

Commercial Temperature Range 0^oC to 70^oC, V_{CC} Max = 5.25V, V_{CC} Min = 4.75V (Note 5)

PARAMETER	SYMBOL	TEST CONDITIONS		V_{CC} (V)	AMBIENT TEMPERATURE (T_A)				UNITS
					25^oC		0^oC TO 70^oC		
		V_I (V)	I_O (mA)		MIN	MAX	MIN	MAX	
High Level Input Voltage	V_{IH}			4.75 to 5.25	2	-	2	-	V
Low Level Input Voltage	V_{IL}			4.75 to 5.25	-	0.8	-	0.8	V
High Level Output Voltage	V_{OH}	V_{IH} or V_{IL}	-15	Min	2.4	-	2.4	-	V
Low Level Output Voltage	V_{OL}	V_{IH} or V_{IL}	48	Min	-	0.55	-	0.55	V
High Level Input Current	I_{IH}	V_{CC}		Max	-	0.1	-	1	µA
Low Level Input Current	I_{IL}	GND		Max	-	-0.1	-	-1	µA
Three-State Leakage Current	I_{OZH}	V_{CC}		Max	-	0.5	-	10	µA
	I_{OZL}	GND		Max	-	-0.5	-	-10	µA
Input Clamp Voltage	V_{IK}	V_{CC} or GND	-18	Min	-	-1.2	-	-1.2	V
Short Circuit Output Current (Note 3)	I_{OS}	V_O = 0 V_{CC} or GND		Max	-60	-	-60	-	mA
Quiescent Supply Current, MSI	I_{CC}	V_{CC} or GND	0	Max	-	8	-	80	µA
Additional Quiescent Supply Current per Input Pin TTL Inputs High, 1 Unit Load	ΔI_{CC}	3.4V (Note 4)		Max	-	1.6	-	1.6	mA

NOTES:

3. Not more than one output should be shorted at one time. Test duration should not exceed 100ms.
4. Inputs that are not measured are at V_{CC} or GND.
5. FCT Input Loading: All inputs are 1 unit load. Unit load is ΔI_{CC} limit specified in Electrical Specifications table, e.g., 1.6mA Max. at 70^oC.

Switching Specifications Over Operating Range FCT Series t_r, t_f = 2.5ns, C_L = 50pF, R_L (Figure 4) (Note 6)

PARAMETER	SYMBOL	V_{CC} (V)	25°C	0°C TO 70°C		UNITS
			TYP	MIN	MAX	
Propagation Delays						
Data to Outputs						
CD74FCT573	t_{PLH}, t_{PHL}	5	5	1.5	8	ns
CD74FCT573AT	t_{PLH}, t_{PHL}	5	3.9	1.5	5.7	ns
$\overline{LE}$ to Outputs						
CD74FCT573	t_{PLH}, t_{PHL}	5	9	2	13	ns
CD74FCT573AT	t_{PLH}, t_{PHL}	5	4.4	2	7	ns
Output Enable Times						
CD74FCT573	t_{PZL}, t_{PZH}	5	7	1.5	12	ns
CD74FCT573AT	t_{PZL}, t_{PZH}	5	6	1.5	8	ns
Output Disable Times						
CD74FCT573	t_{PLZ}, t_{PHZ}	5	6	1.5	7.5	ns
CD74FCT573AT	t_{PLZ}, t_{PHZ}	5	4	1.5	5.8	ns
Power Dissipation Capacitance	C_{PD} (Note 7)	-	34	-	-	pF
Minimum (Valley) V_{OHV} During Switching of Other Outputs (Output Under Test Not Switching)	V_{OHV} (Figure 1)	5	0.5	-	-	V
Maximum (Peak) V_{OLP} During Switching of Other Outputs (Output Under Test Not Switching)	V_{OLP} (Figure 1)	5	1	-	-	V
Input Capacitance	C_I	-	-	-	10	pF
Three-State Output Capacitance	C_O	-	-	-	15	pF

NOTES:

6. 5V: Min is at 5.25V for 0°C to 70°C, Max is at 4.75V for 0°C to 70°C, Typ is at 5V.
7. C_{PD}, measured per flip-flop, is used to determine the dynamic power consumption.
   P_D (per package) = V_{CC} I_{CC} + $\Sigma(V_{CC}^2$ f_I C_{PD} + V_O^2 f_O C_L + V_{CC} ΔI_{CC} D) where:
   V_{CC} = supply voltage
   ΔI_{CC} = flow through current x unit load
   C_L = output load capacitance
   D = duty cycle of input high
   f_O = output frequency
   f_I = input frequency

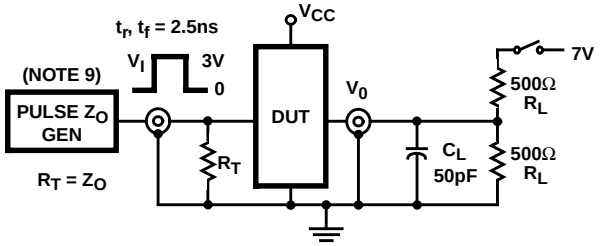
Prerequisite for Switching

PARAMETER	SYMBOL	V_{CC} (V)	25°C	0°C TO 70°C		UNITS
			TYP	MIN	MAX	
Data to Latch Enable Setup Time	t_{SU}	5 (Note 8)	-	2	-	ns
Data to Latch Enable Hold Time	t_H	5	-	1.5	-	ns
Latch Enable Pulse Width						
CD74FCT573	t_W	5	-	6	-	ns
CD74FCT573AT	t_W	5	-	5	-	ns

NOTE:

8. 5V: Minimum is at 4.75V for 0°C to 70°C, Typical is at 5V.

Test Circuits and Waveforms



NOTE:

9. Pulse Generator for All Pulses: Rate ≤ 1.0MHz; Z_{OUT} ≤ 50Ω; t_f, t_r ≤ 2.5ns.

FIGURE 1. TEST CIRCUIT

SWITCH POSITION

TEST	SWITCH
t_{PLZ}, t_{PZL}, Open Drain	Closed
t_{PHZ}, t_{PZH}, t_{PLH}, t_{PHL}	Open

DEFINITIONS:

C_L = Load capacitance, includes jig and probe capacitance.

R_T = Termination resistance, should be equal to Z_{OUT} of the Pulse Generator.

V_{IN} = 0V to 3V.

Input: $t_r = t_f$ = 2.5ns (10% to 90%), unless otherwise specified

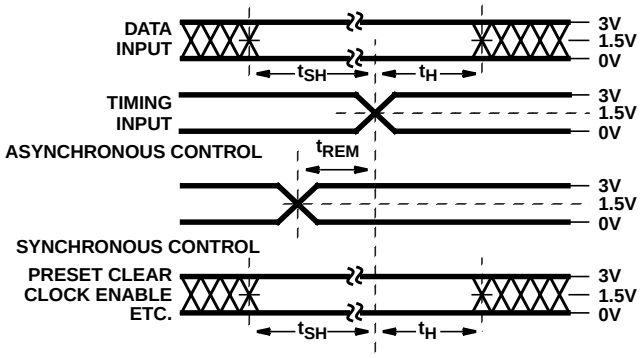


FIGURE 2. SETUP, HOLD, AND RELEASE TIMING

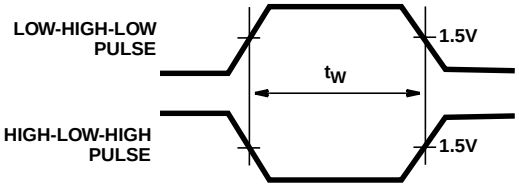


FIGURE 3. PULSE WIDTH

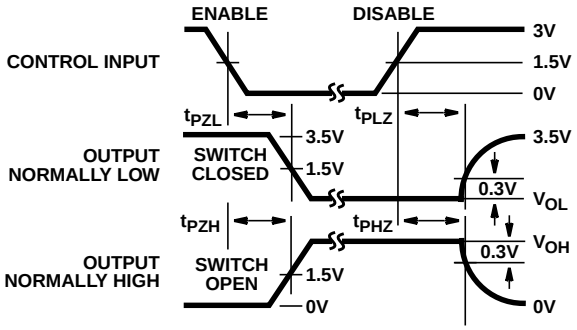


FIGURE 4. ENABLE AND DISABLE TIMING

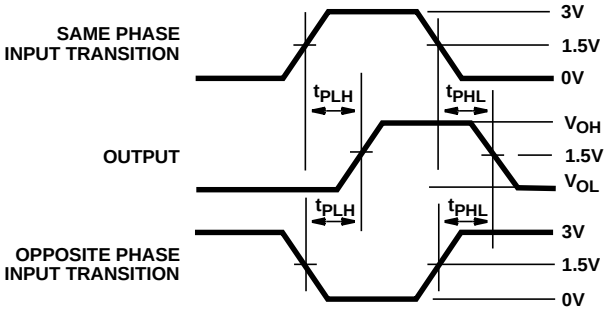
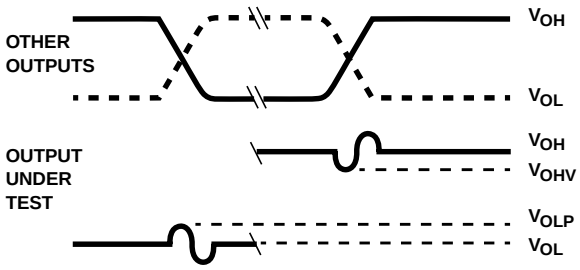


FIGURE 5. PROPAGATION DELAY

Test Circuits and Waveforms (Continued)



NOTES:

10. V_{OLP} is measured with respect to a ground reference near the output under test. V_{OHV} is measured with respect to V_{OH}.
11. Input pulses have the following characteristics:
    $P_{RR} \leq 1MHz$, $t_r = 2.5ns$, $t_f = 2.5ns$, skew 1ns.
12. R.F. fixture with 700MHz design rules required. IC should be soldered into test board and bypassed with 0.1µF capacitor. Scope and probes require 700MHz bandwidth.

FIGURE 6. SIMULTANEOUS SWITCHING TRANSIENT WAVEFORMS

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